



Huazhong University
of Science & Technology

Electronic Circuit of Communications

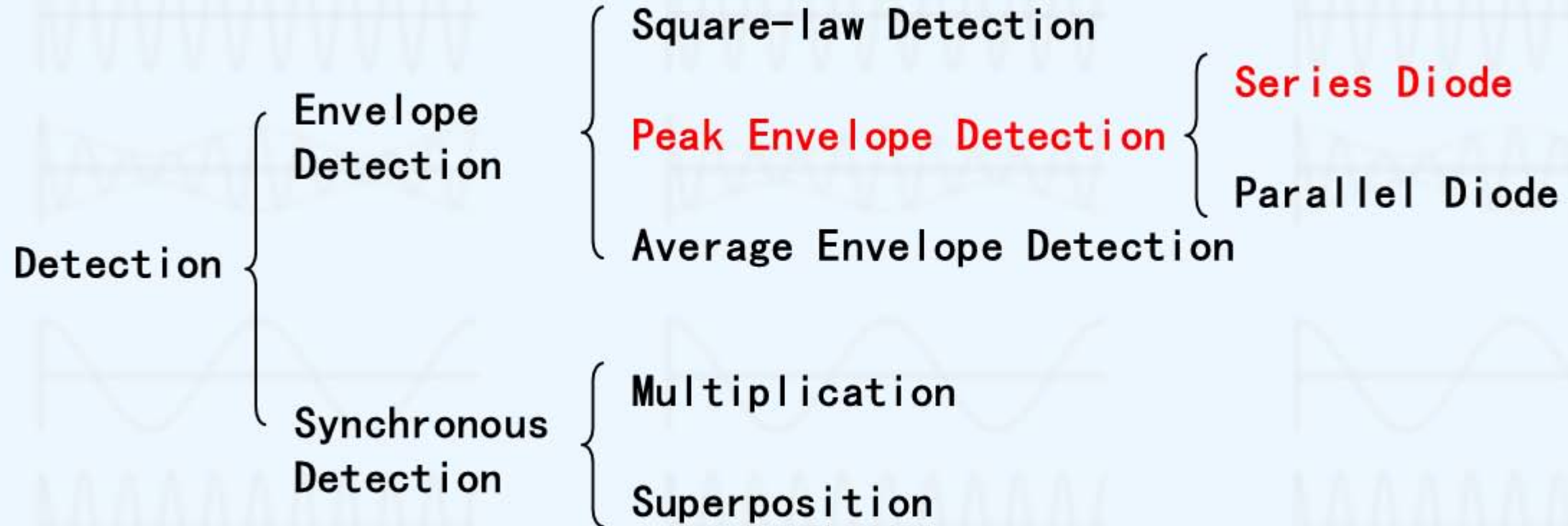
School of Electronic Information
and Communications

Jiaqing Huang

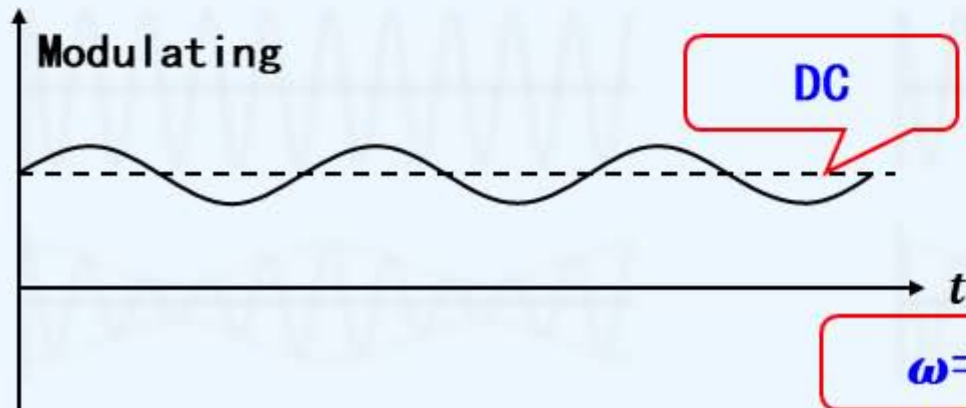
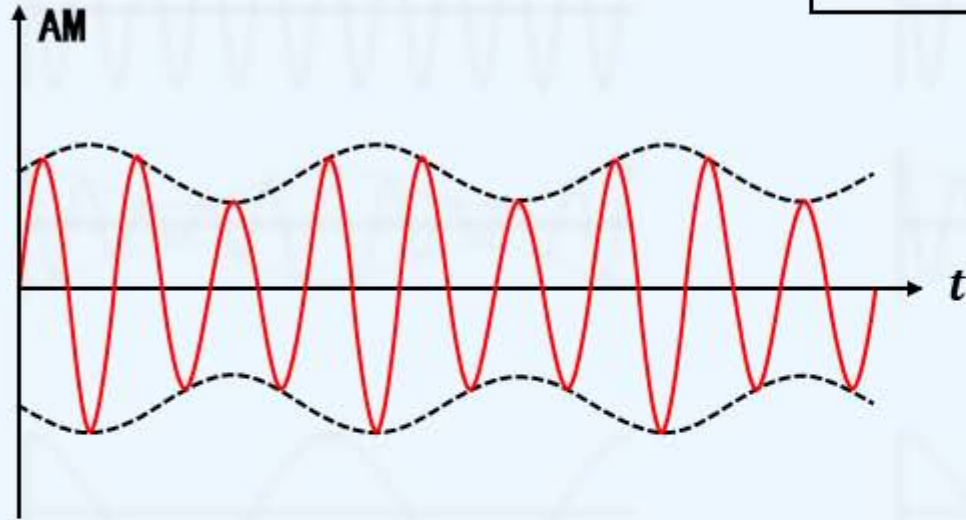
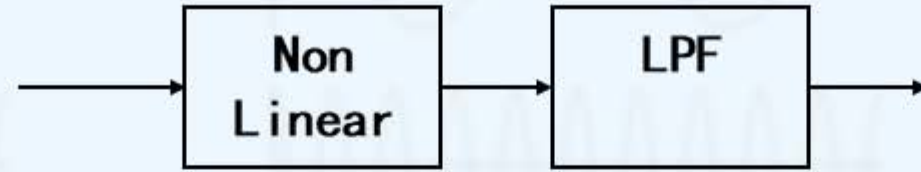


Peak Envelope Detection

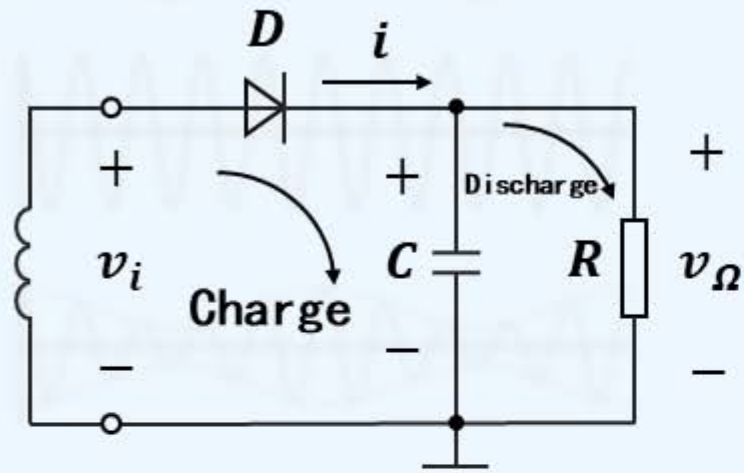
Detection – Classification



Envelope Detection (Single-Tone AM)



Peak Envelope Detection



RC : Detector Load
LPF

$$\frac{1}{\omega_0 C} \ll R \quad \frac{1}{\Omega_{\max} C} \gg R$$

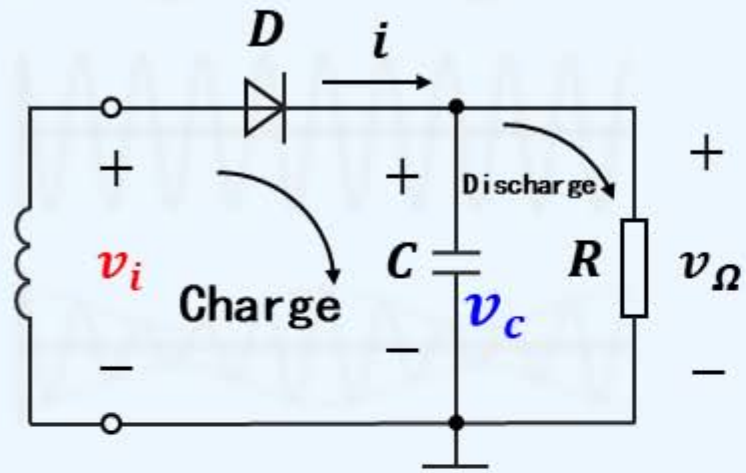
➤ Principle:

- ① Diode unilateral conductivity
- ② RC Time constant

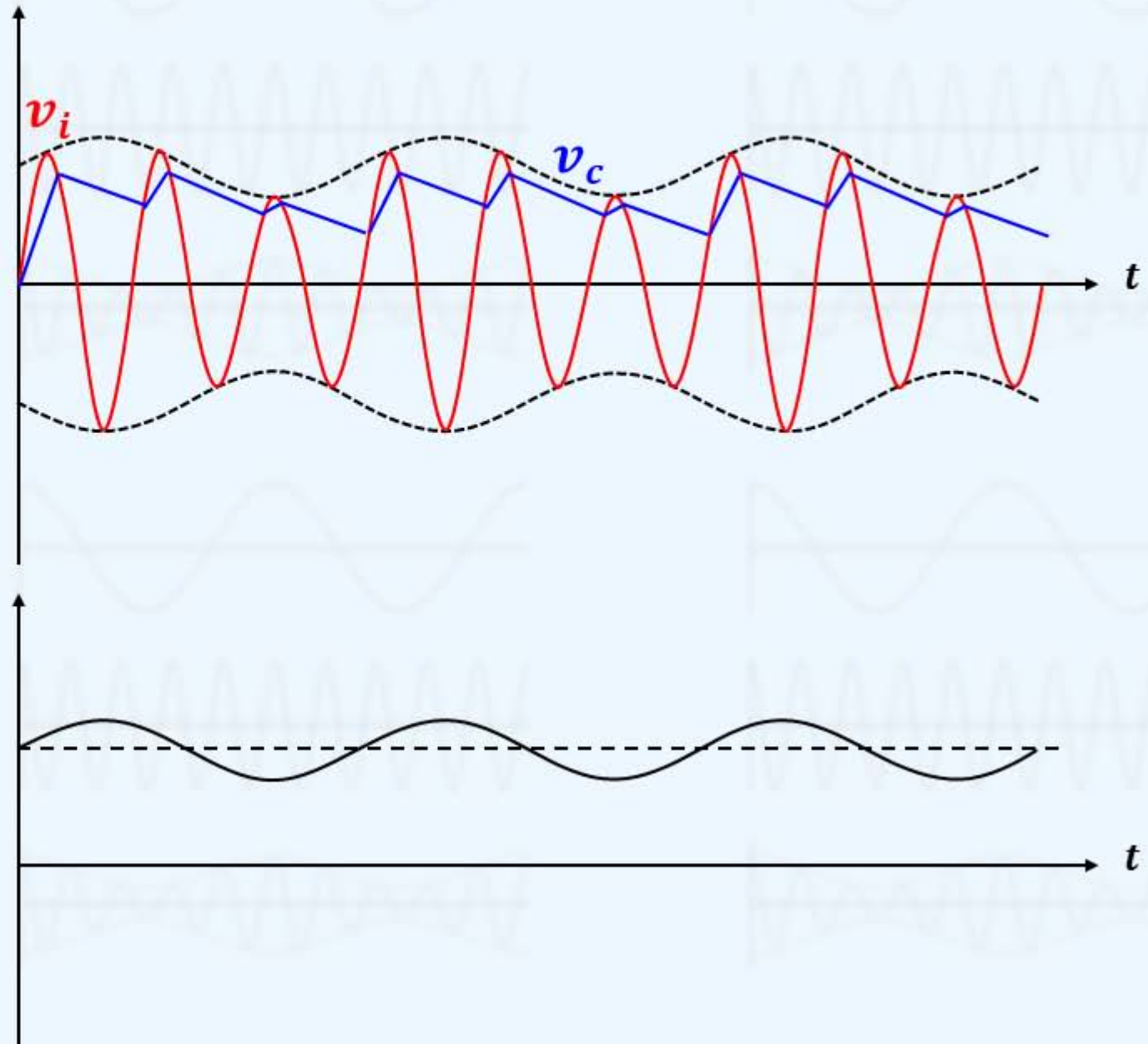
Charge $R_d C \ll RC$ Discharge

R_d : D Resistance

Peak Envelope Detection



$$R_d C \ll RC$$



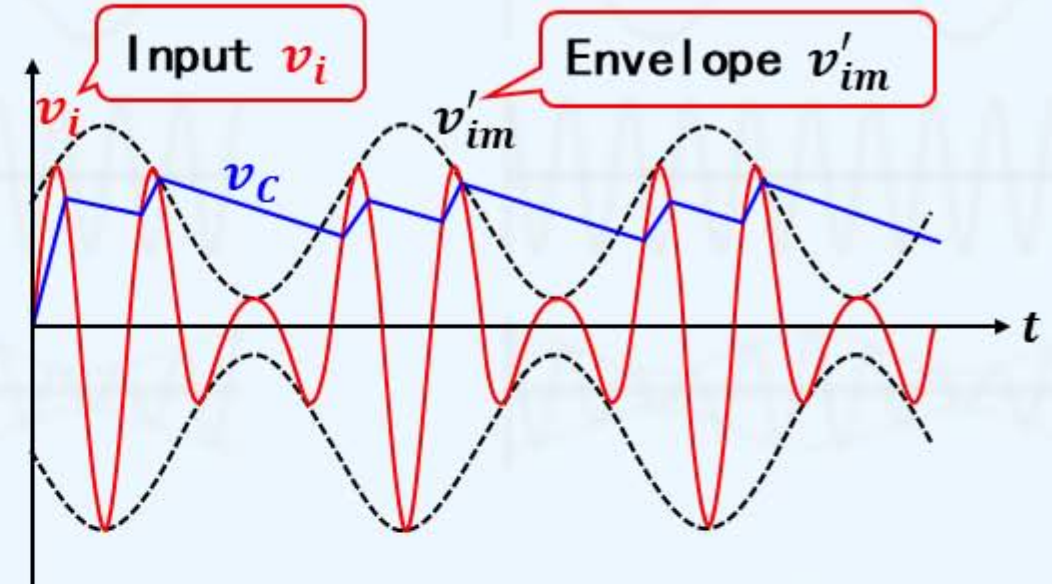
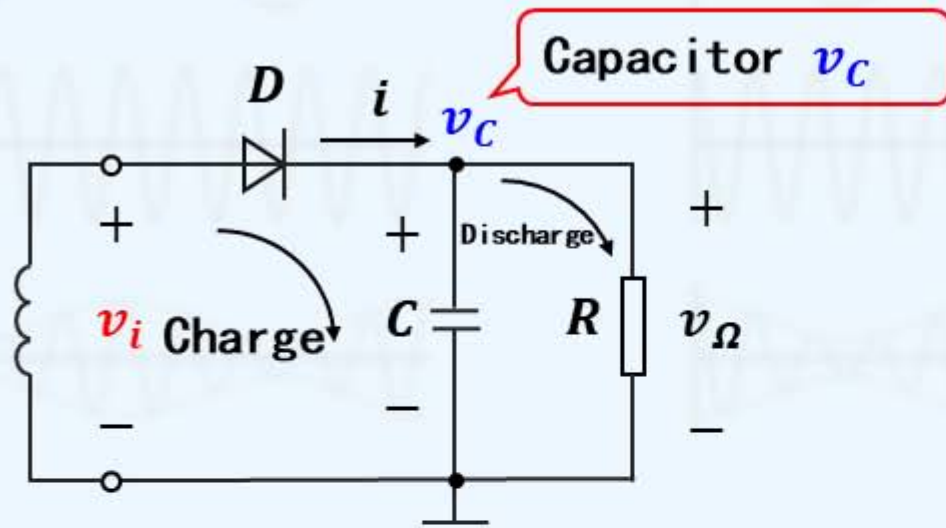


Envelope Detection Distortion

Envelope Detection Distortion

- Classification** {
- ① Diagonal Distortion (Inert)
 - ② Negative Peak Clipping Distortion
 - ③ Nonlinear Distortion
 - ④ Frequency Distortion

Envelope Detection Distortion – Diagonal Distortion

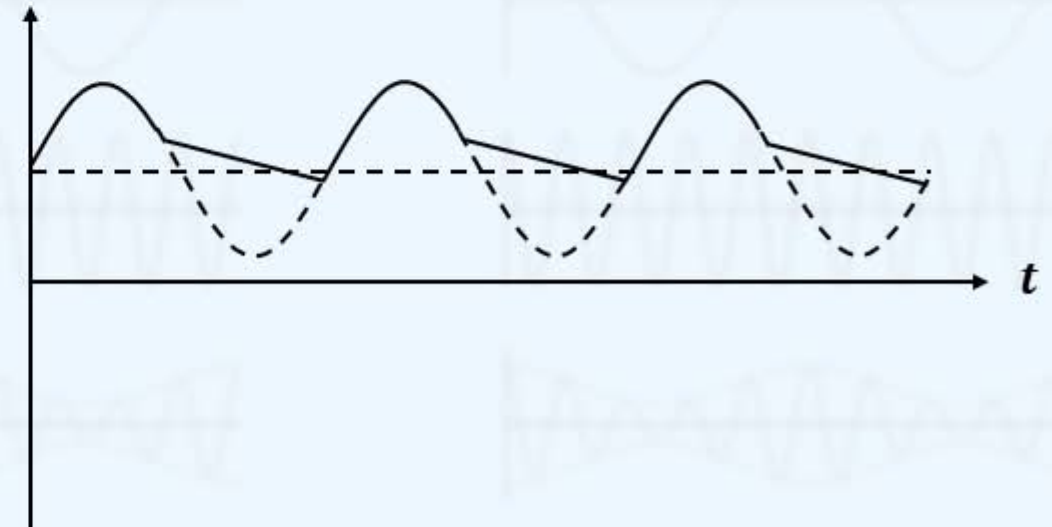


Reason:

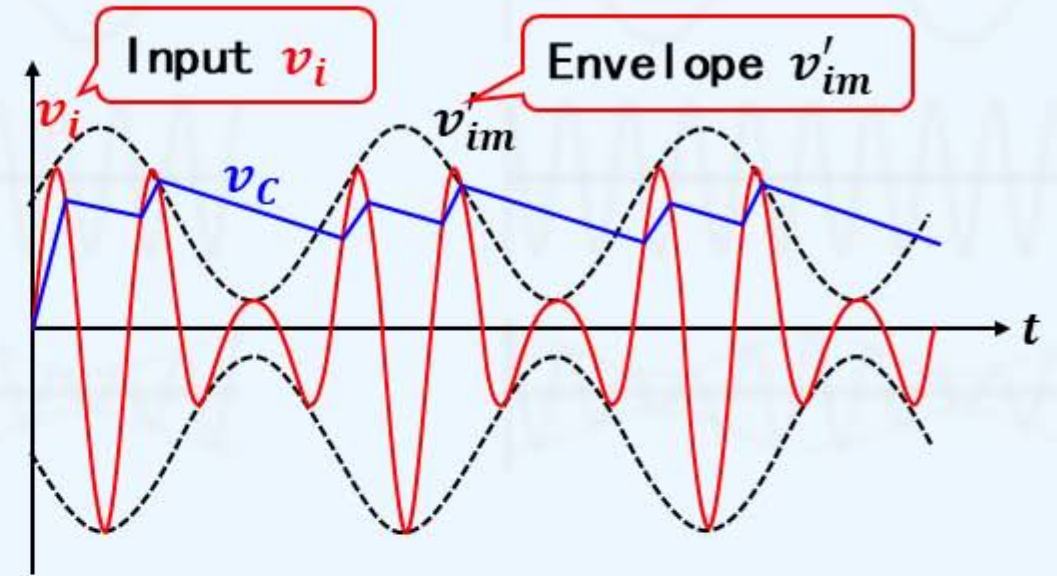
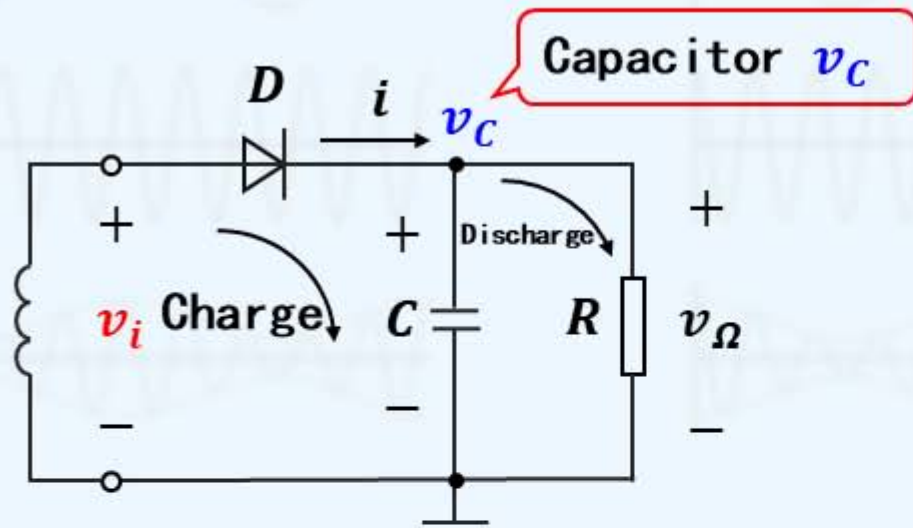
Time constant RC is very big

C discharge is slow

v_C cannot catch v'_{im}



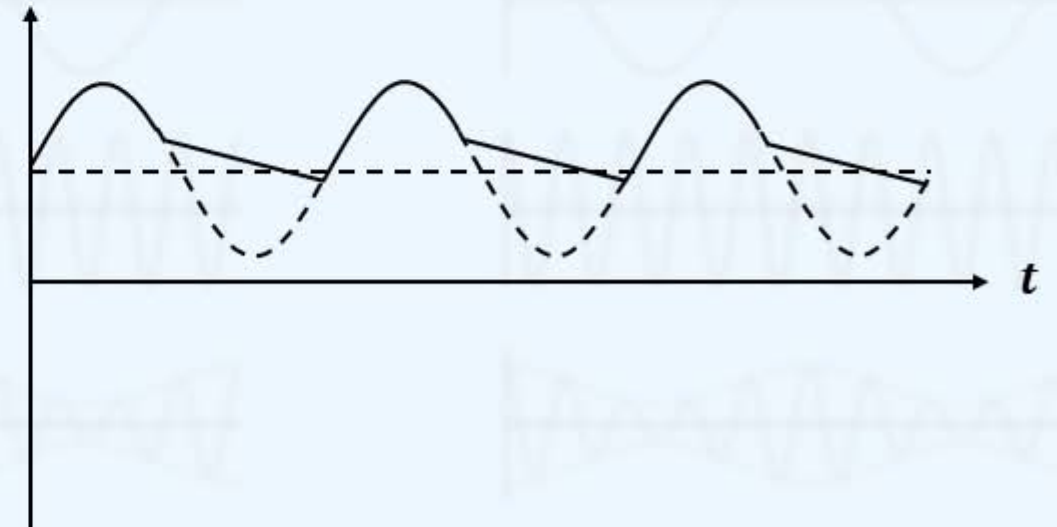
Envelope Detection Distortion – Diagonal Distortion



Method:

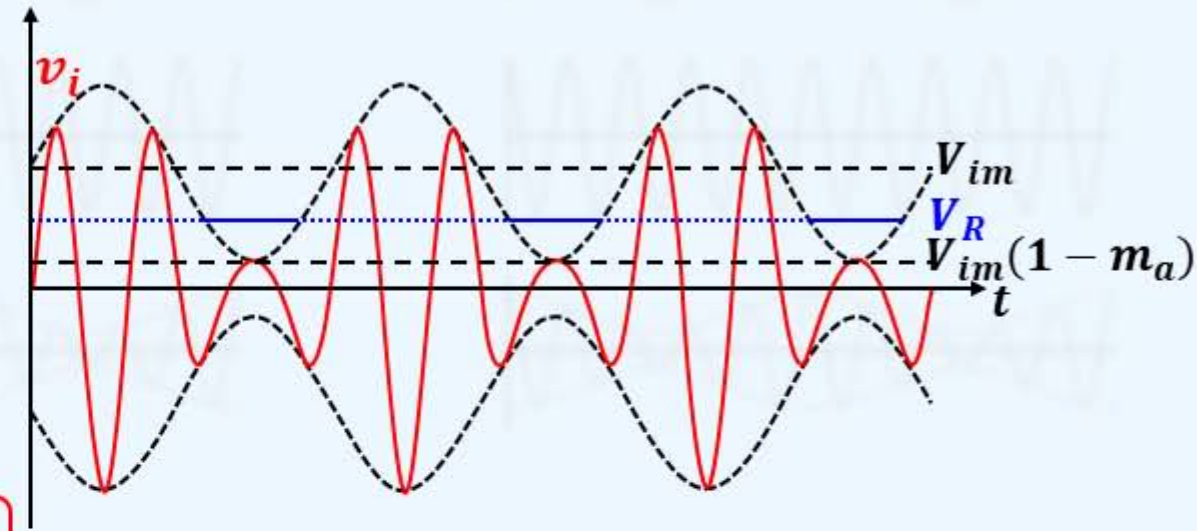
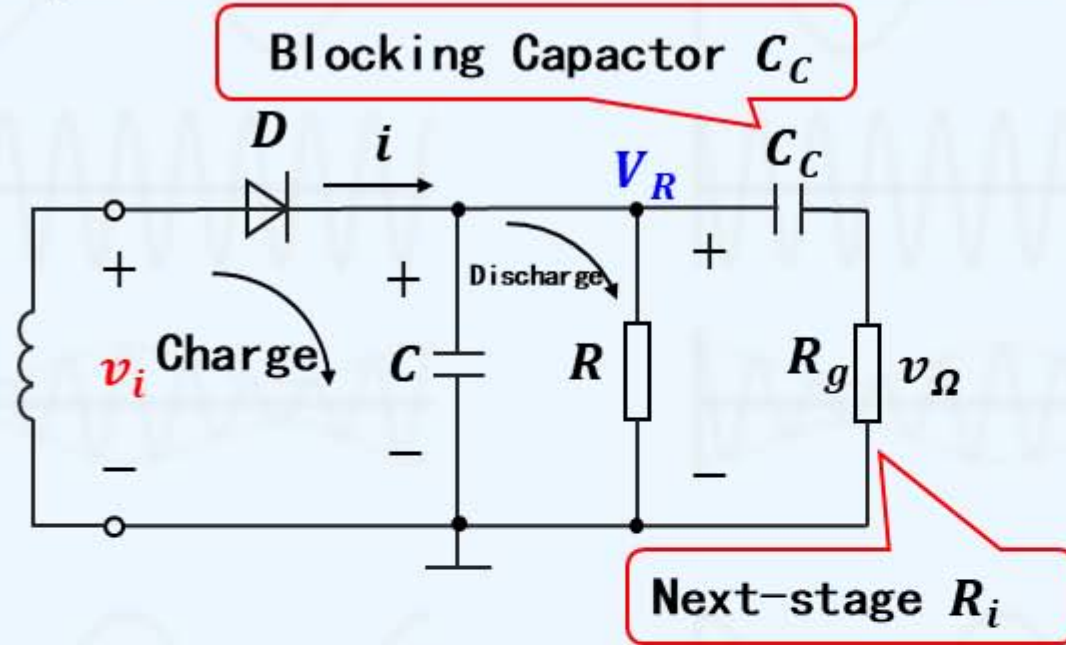
$$\frac{dv_c}{dt} > \frac{dv'_{im}}{dt}$$

$$\Omega_{max} RC \leq \frac{\sqrt{1 - m_a^2}}{m_a}$$



Engineering $\Omega_{max} RC \leq 1.5$

Envelope Detection Distortion - Negative Peak Clipping

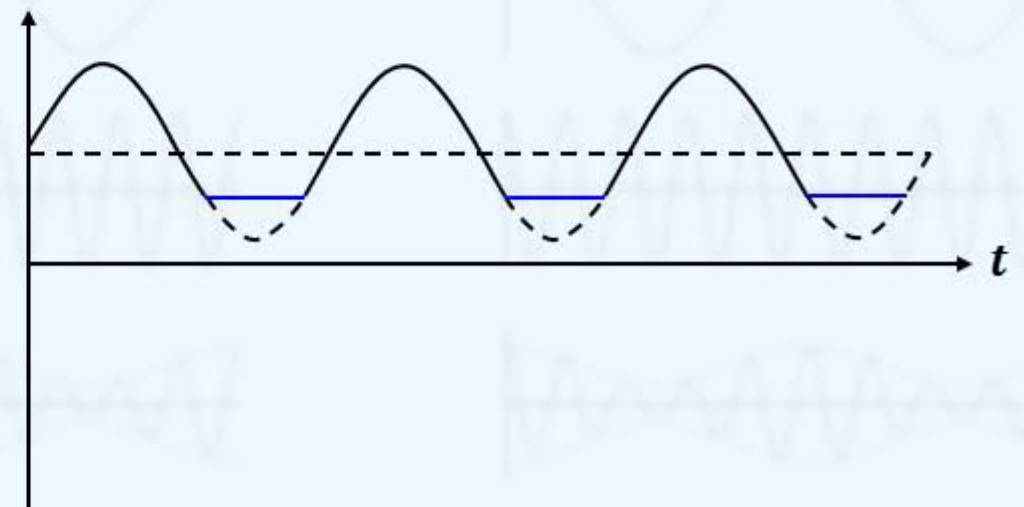


Reason:

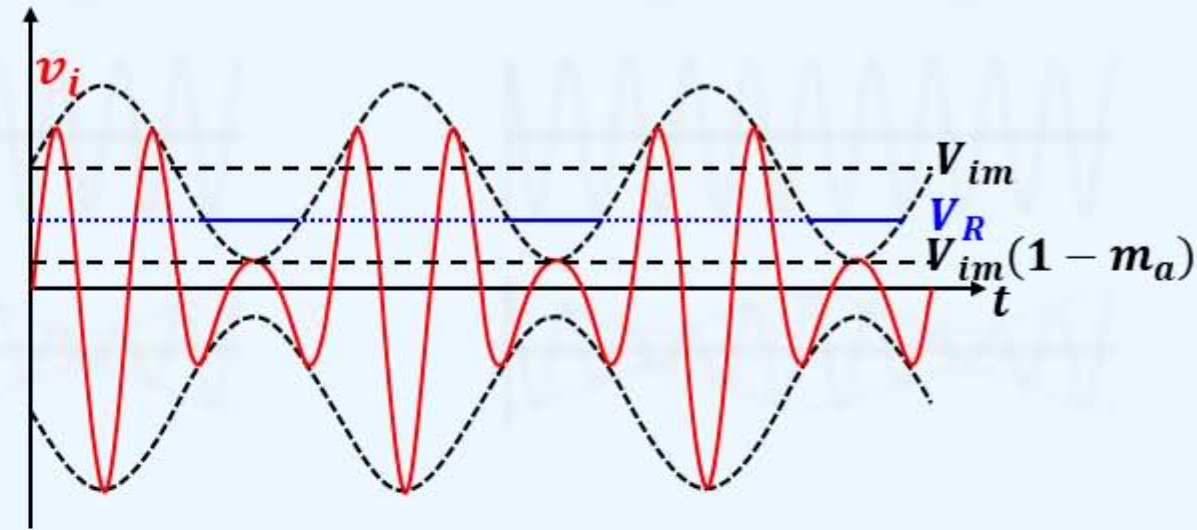
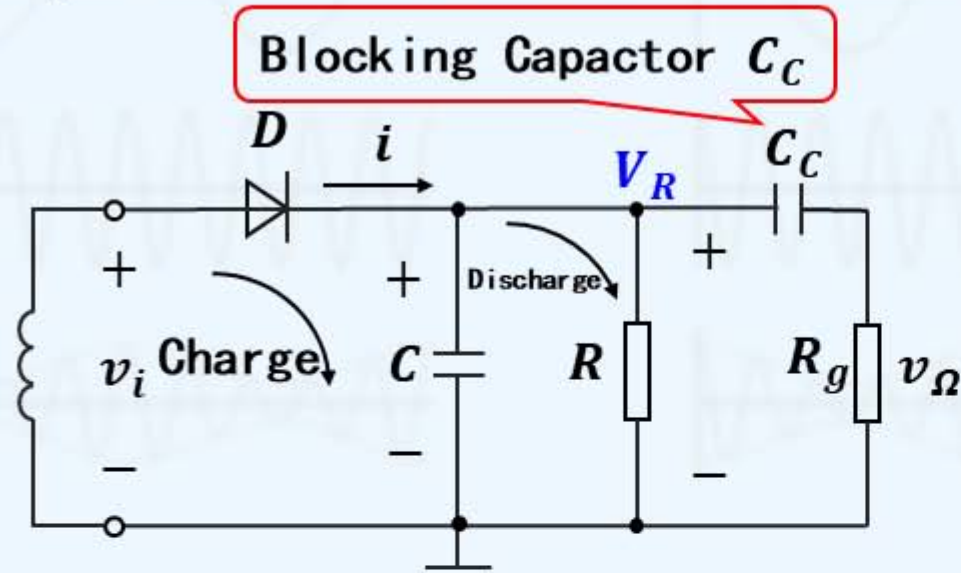
$C_C \uparrow$, voltage $\approx V_{im}$

$$V_R = \frac{R}{R + R_g} V_{im}$$

$$V_R > V_{im}(1 - m_a)$$



Envelope Detection Distortion - Negative Peak Clipping



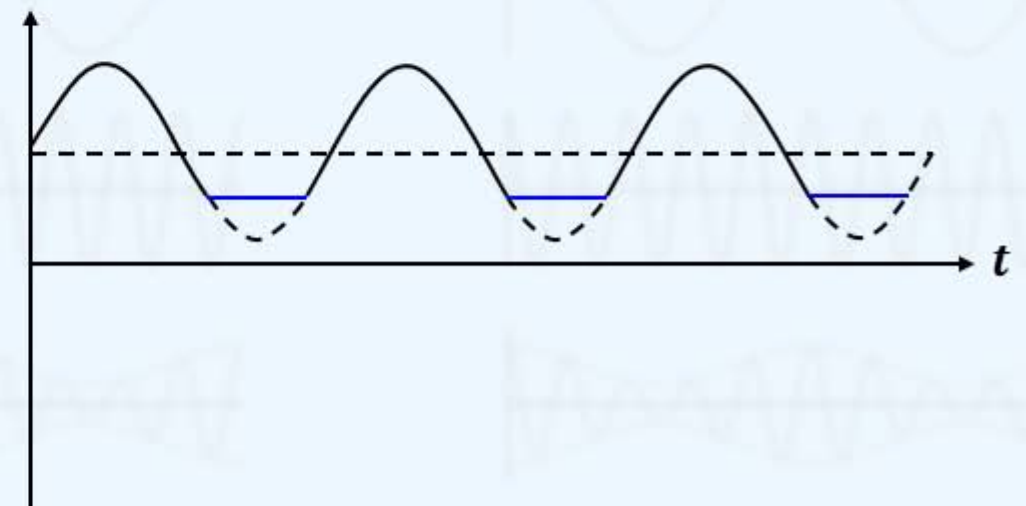
Method:

$$V_{im}(1 - m_a) > V_R = \frac{R}{R + R_g} V_{im}$$

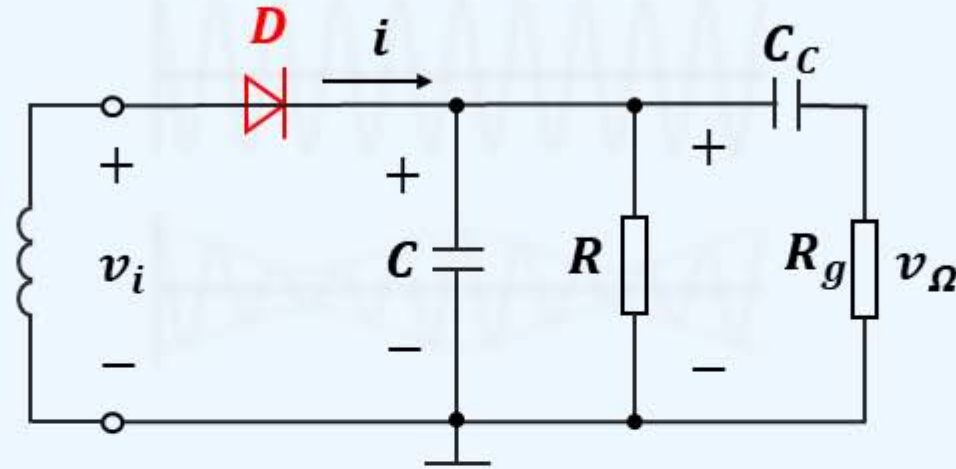
$$m_a < \frac{R_g}{R + R_g} = \frac{R \parallel R_g}{R} = \frac{R_{\sim}}{R}$$

AC Resistance

DC Resistance



Envelope Detection Distortion - Nonlinear Distortion



Reason:

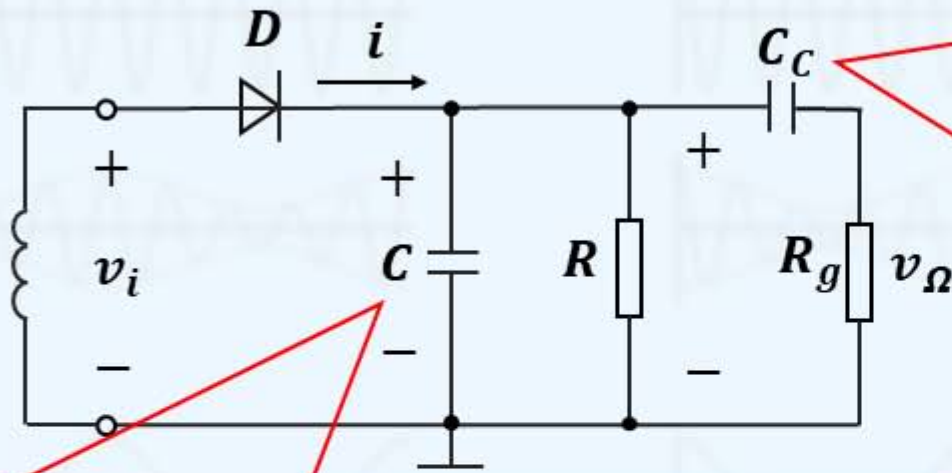
- Nonlinear Diode

Method:

- R big enough

Envelope Detection Distortion – Frequency Distortion

$$C_c \approx \text{several } \mu F$$



Reason2: Blocking C_c
influences Ω_{min}

Method:

$$\frac{1}{\Omega_{min} C_c} \ll R_g$$

Reason1: High-pass filter C
influences Ω_{max}

Method:

$$\frac{1}{\Omega_{max} C} \gg R$$

$$C \approx 0.01 \mu F$$

Summary

By C

Diagonal Distortion

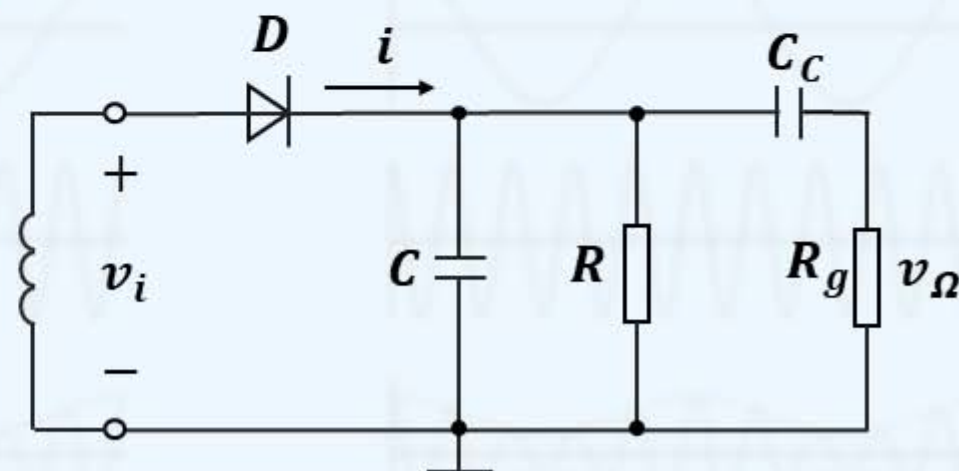
Negative Peak Clipping Distortion

Diode cut-off

Nonlinear Distortion

By C_C

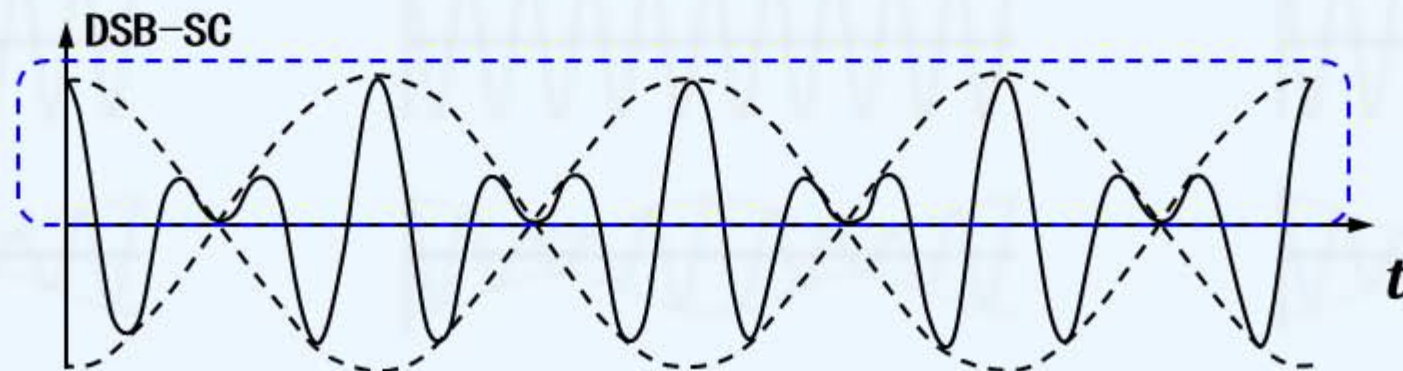
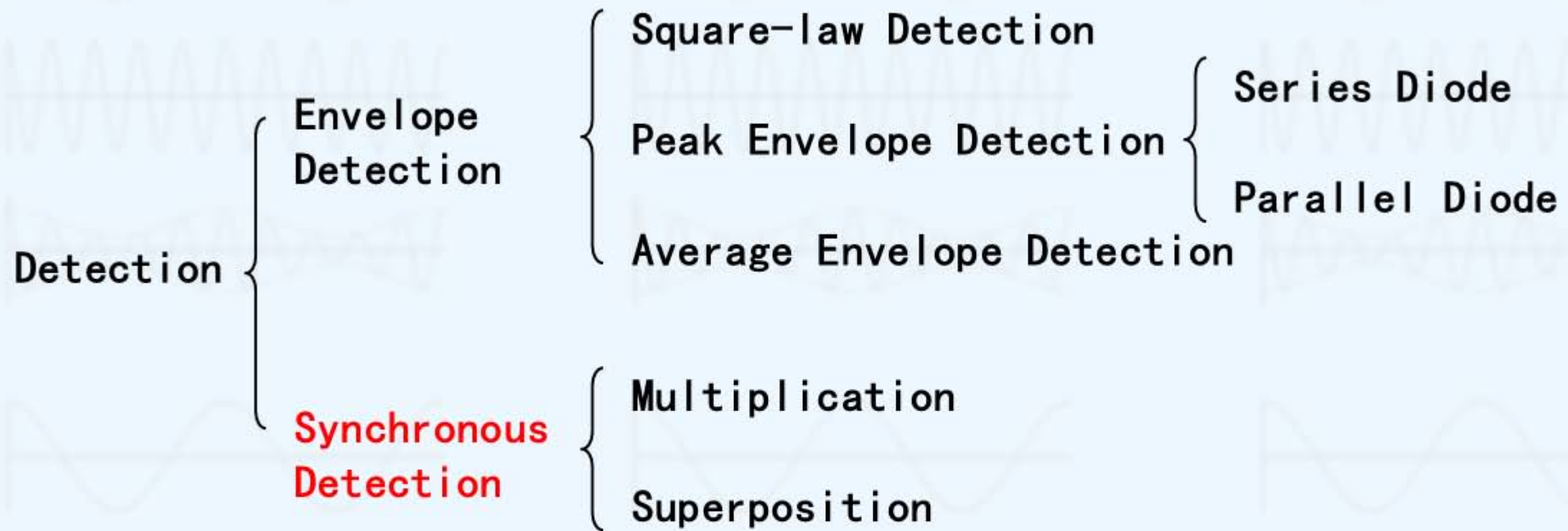
Frequency Distortion





Synchronous Detection

Detection – Classification



Synchronous Detection – Multiplication

$$\begin{aligned}v_1 &= V_s(\cos \Omega t \cos \omega_0 t)V_0 \cos \omega_0 t \\&= V_s V_0 \cos \Omega t (\cos \omega_0 t)^2 \\&= V_s V_0 \cos \Omega t \cdot \frac{1}{2}(1 + \cos 2\omega_0 t) \\&= \frac{1}{2} V_s V_0 \cos \Omega t + \frac{1}{2} V_s V_0 \cos \Omega t \cos 2\omega_0 t \\&= \frac{1}{2} V_s V_0 \cos \Omega t + \frac{1}{4} V_s V_0 \cos(2\omega_0 - \Omega)t + \frac{1}{4} V_s V_0 \cos(2\omega_0 + \Omega)t\end{aligned}$$

(DSB-SC) :

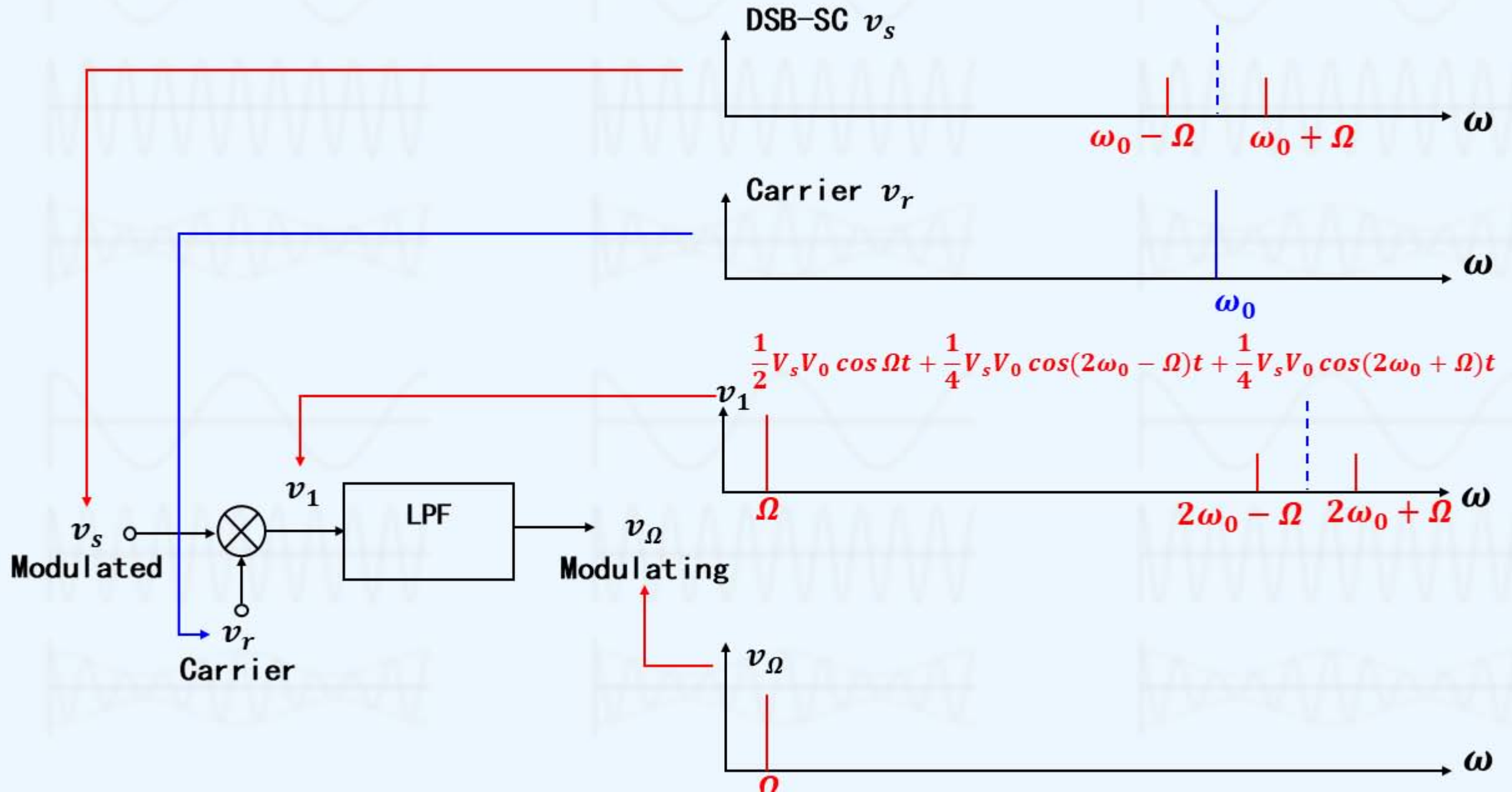
$$v_s = V_s \cos \Omega t \cos \omega_0 t$$



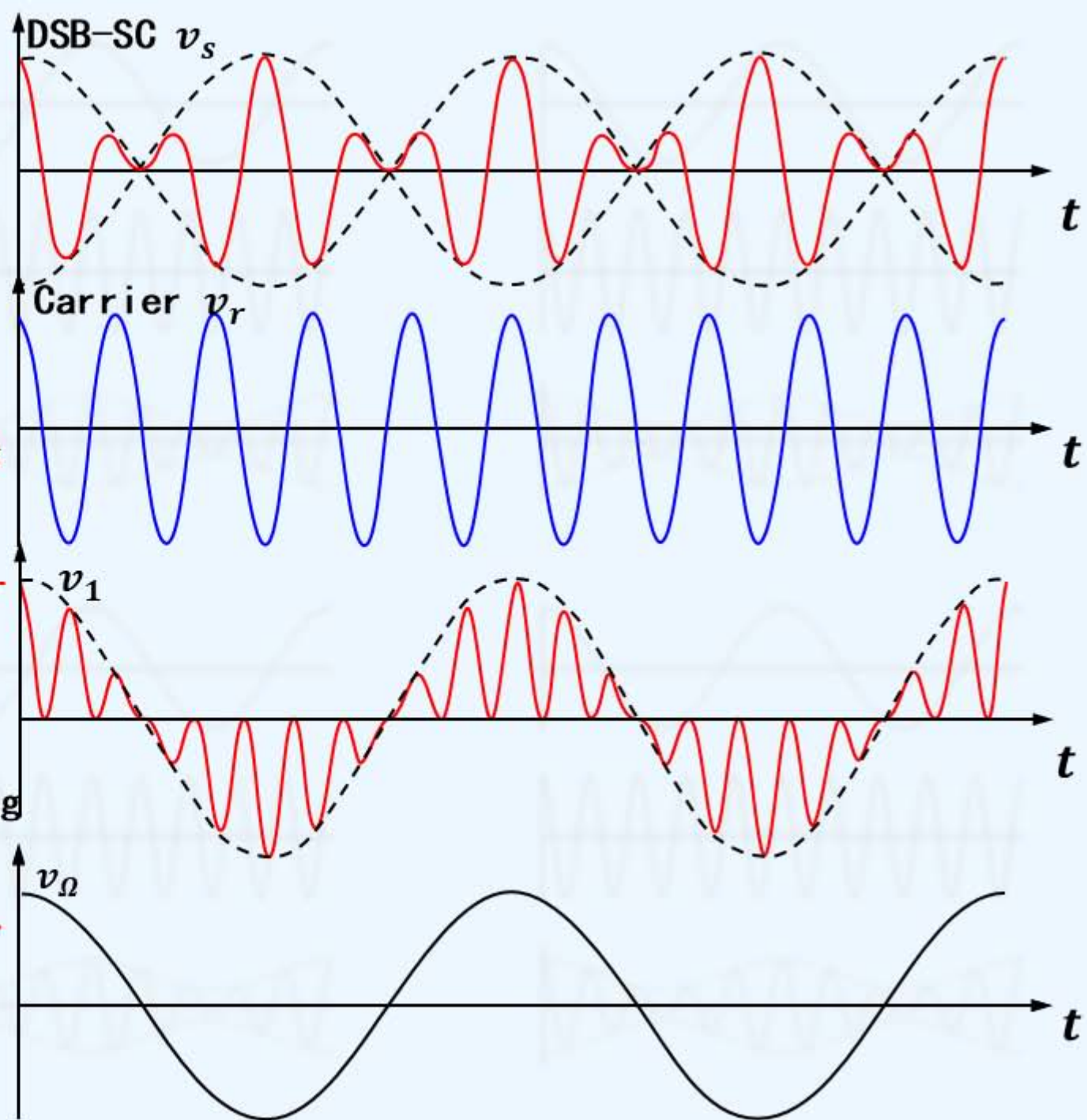
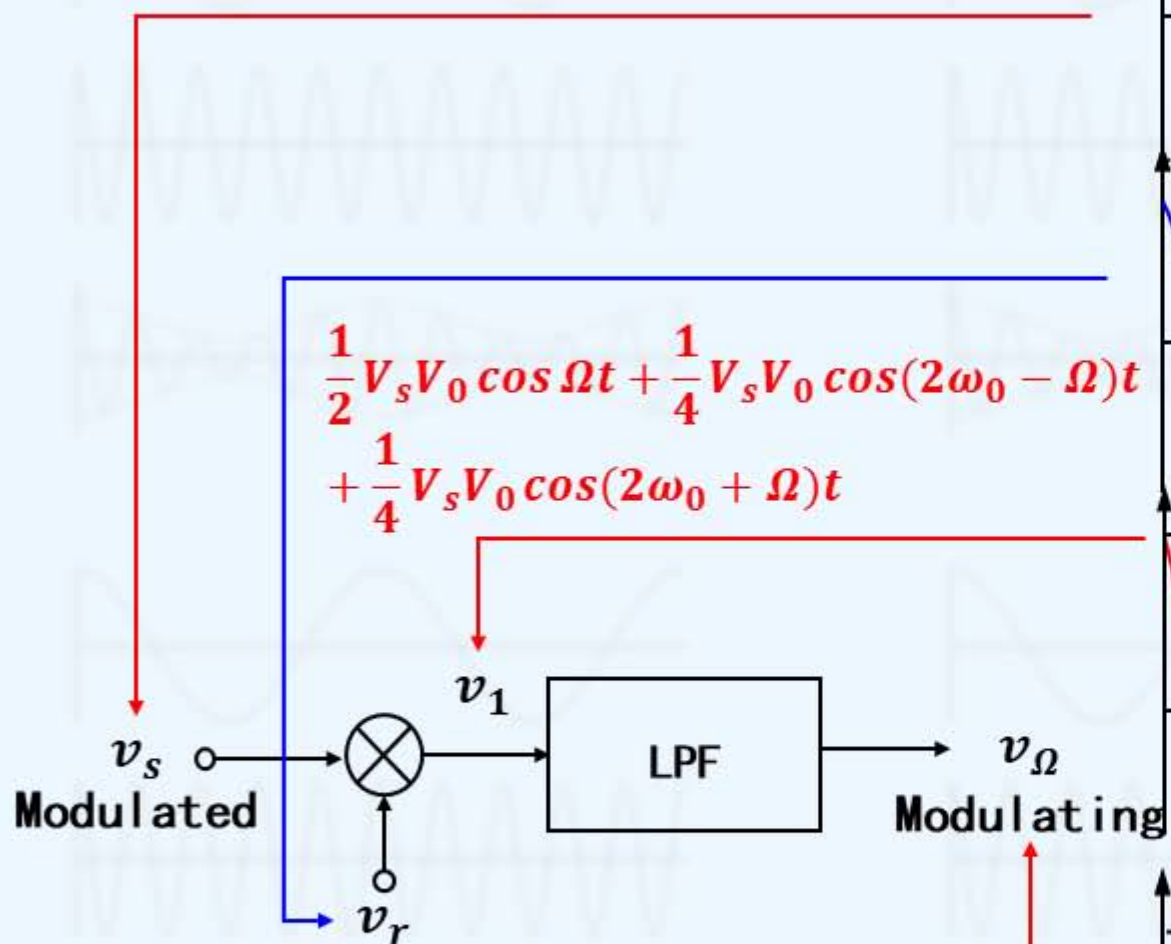
$$v_r = V_0 \cos \omega_0 t$$

Synchronous

Synchronous Detection – Multiplication

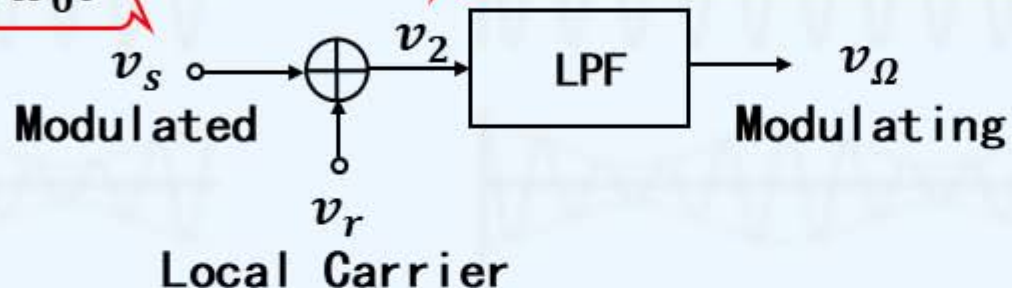


Synchronous Detection



Synchronous Detection – Superposition

$$v_s = V_s \cos \Omega t \cos \omega_0 t$$

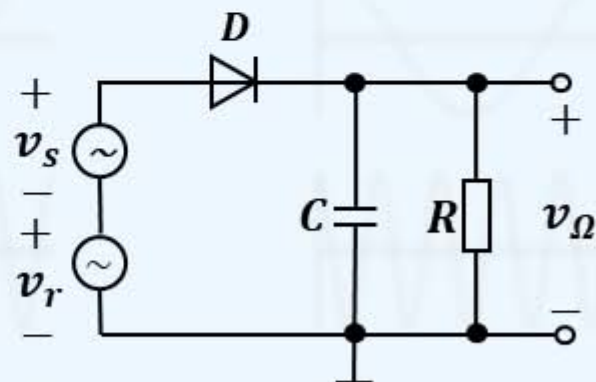
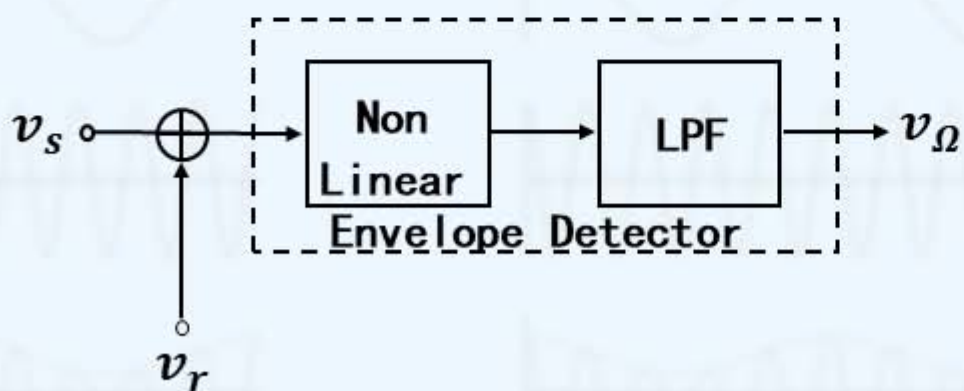


$$v_2 = v_s + v_r = V_r \left(1 + \frac{V_s}{V_r} \cos \Omega t \right) \cos \omega_0 t$$

$$\text{If } V_s < V_r, \quad m_a = \frac{V_s}{V_r} < 1$$

⇒ Using envelope detection

$$v_r = V_0 \cos \omega_0 t$$



Synchronous Detection using Diode

Summary

